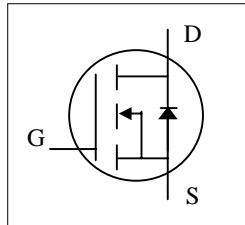




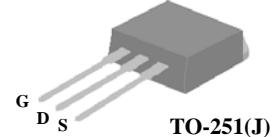
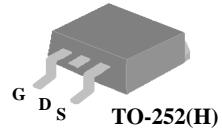
- ▼ 100% Avalanche Test
- ▼ Fast Switching Characteristics
- ▼ Simple Drive Requirement



$BV_{DSS}$	600V
$R_{DS(ON)}$	12Ω
$I_D$	1A

### Description

The TO-252 package is widely preferred for commercial-industrial surface mount applications and suited for AC/DC converters. The through-hole version (AP01L60J) is available for low-profile applications.



### Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	600	V
$V_{GS}$	Gate-Source Voltage	$\pm 30$	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	1	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	0.8	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	3	A
$P_D @ T_C = 25^\circ C$	Total Power Dissipation	29	W
	Linear Derating Factor	0.232	W/°C
$E_{AS}$	Single Pulse Avalanche Energy <sup>2</sup>	0.5	mJ
$I_{AR}$	Avalanche Current	1	A
$E_{AR}$	Repetitive Avalanche Energy	0.5	mJ
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

### Thermal Data

Symbol	Parameter	Value	Units
$R_{thj-c}$	Maximum Thermal Resistance, Junction-case	4.3	°C/W
$R_{thj-a}$	Maximum Thermal Resistance, Junction-ambient (PCB mount) <sup>4</sup>	62.5	°C/W
$R_{thj-a}$	Maximum Thermal Resistance, Junction-ambient	110	°C/W



### Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=1\text{mA}$	600	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Breakdown Voltage Temperature Coefficient	Reference to $25^\circ\text{C}$ , $I_{\text{D}}=1\text{mA}$	-	0.8	-	$\text{V}/^\circ\text{C}$
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance <sup>3</sup>	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=0.5\text{A}$	-	-	12	$\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\text{\mu A}$	2	-	4	V
$g_{\text{fs}}$	Forward Transconductance	$V_{\text{DS}}=10\text{V}, I_{\text{D}}=0.5\text{A}$	-	0.8	-	S
$I_{\text{DSS}}$	Drain-Source Leakage Current	$V_{\text{DS}}=600\text{V}, V_{\text{GS}}=0\text{V}$	-	-	10	$\text{uA}$
	Drain-Source Leakage Current ( $T_j=125^\circ\text{C}$ )	$V_{\text{DS}}=480\text{V}, V_{\text{GS}}=0\text{V}$	-	-	100	$\text{uA}$
$I_{\text{GSS}}$	Gate-Source Leakage	$V_{\text{GS}}=\pm 30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
$Q_g$	Total Gate Charge <sup>3</sup>	$I_{\text{D}}=1\text{A}$	-	4.0	-	nC
$Q_{\text{gs}}$	Gate-Source Charge	$V_{\text{DS}}=480\text{V}$	-	1.0	-	nC
$Q_{\text{gd}}$	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=10\text{V}$	-	1.1	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time <sup>3</sup>	$V_{\text{DD}}=300\text{V}$	-	6.6	-	ns
$t_r$	Rise Time	$I_{\text{D}}=1\text{A}$	-	5.0	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_G=3.3\Omega, V_{\text{GS}}=10\text{V}$	-	11.7	-	ns
$t_f$	Fall Time	$R_D=300\Omega$	-	9.2	-	ns
$C_{\text{iss}}$	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	170	-	pF
$C_{\text{oss}}$	Output Capacitance	$V_{\text{DS}}=25\text{V}$	-	30.7	-	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance	f=1.0MHz	-	5.1	-	pF

### Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$I_S$	Continuous Source Current ( Body Diode )	$V_D=V_G=0\text{V}, V_S=1.2\text{V}$	-	-	1	A
$I_{\text{SM}}$	Pulsed Source Current ( Body Diode ) <sup>1</sup>		-	-	5	A
$V_{\text{SD}}$	Forward On Voltage <sup>3</sup>	$T_j=25^\circ\text{C}, I_S=1\text{A}, V_{\text{GS}}=0\text{V}$	-	-	1.2	V

#### Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Starting  $T_j=25^\circ\text{C}$  ,  $V_{\text{DD}}=50\text{V}$  ,  $L=1.0\text{mH}$  ,  $R_G=25\Omega$  ,  $I_{\text{AS}}=1.0\text{A}$ .
- 3.Pulse test
- 4.Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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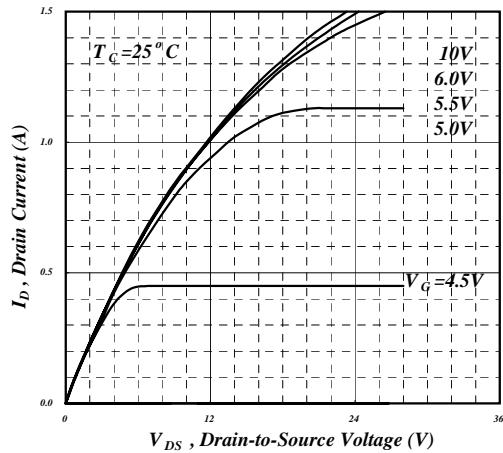


Fig 1. Typical Output Characteristics

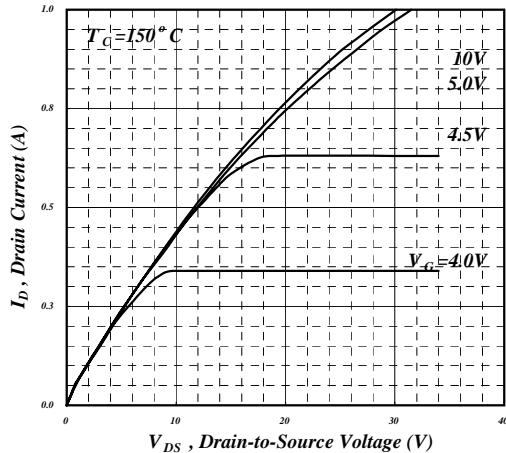


Fig 2. Typical Output Characteristics

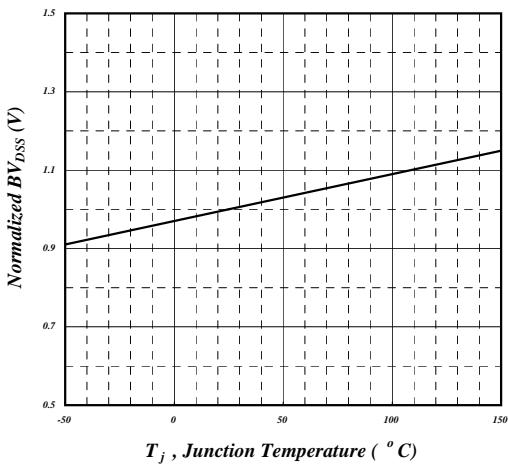
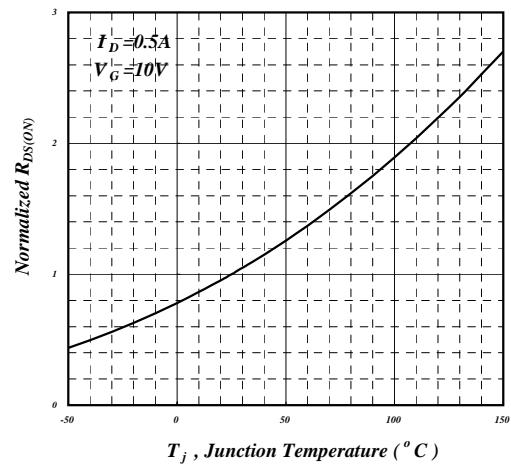
Fig 3. Normalized  $BV_{DSS}$  v.s. Junction Temperature

Fig 4. Normalized On-Resistance v.s. Junction Temperature

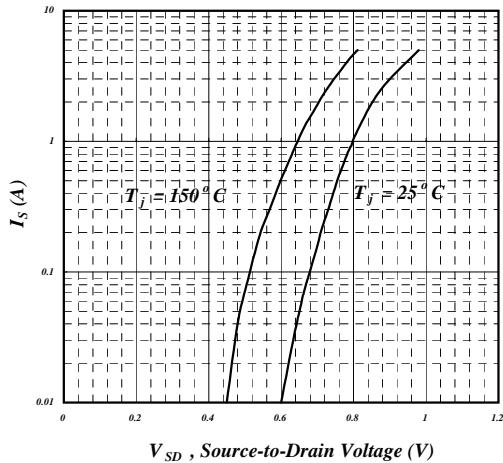


Fig 5. Forward Characteristic of Reverse Diode

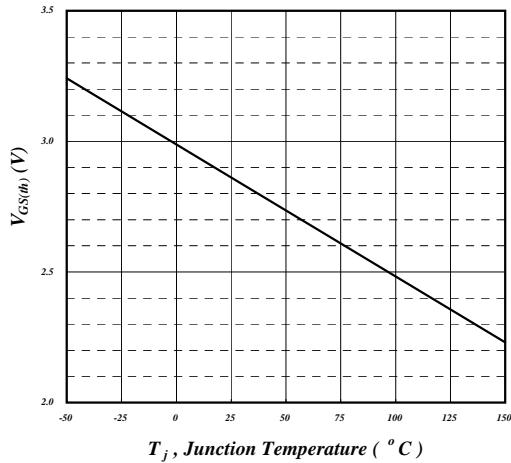
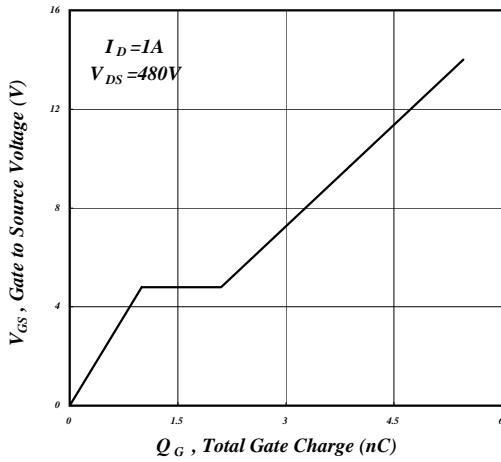
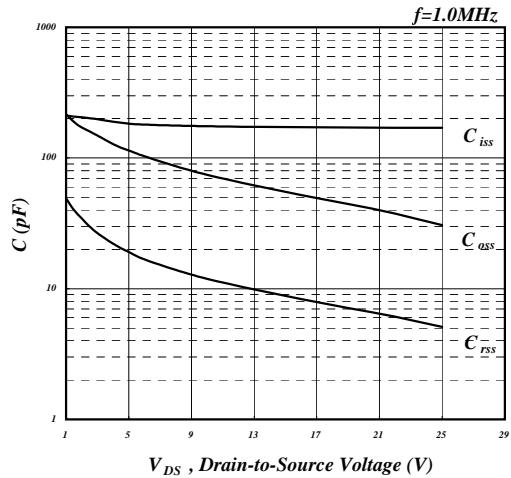


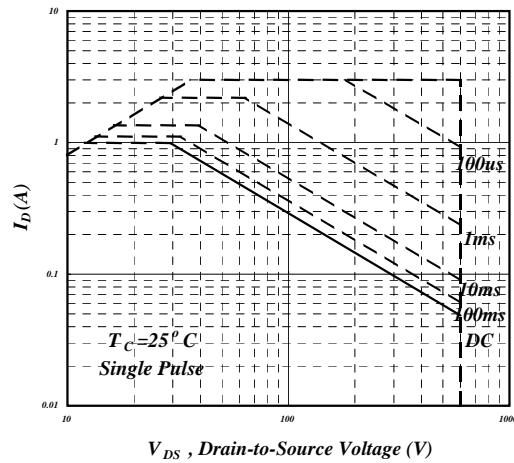
Fig 6. Gate Threshold Voltage v.s. Junction Temperature



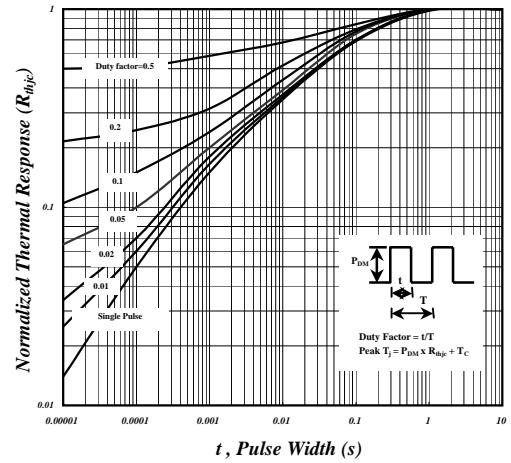
**Fig 7. Gate Charge Characteristics**



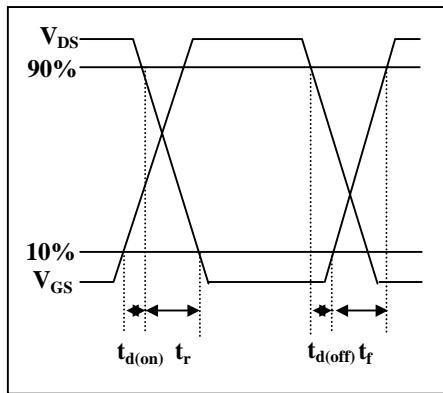
**Fig 8. Typical Capacitance Characteristics**



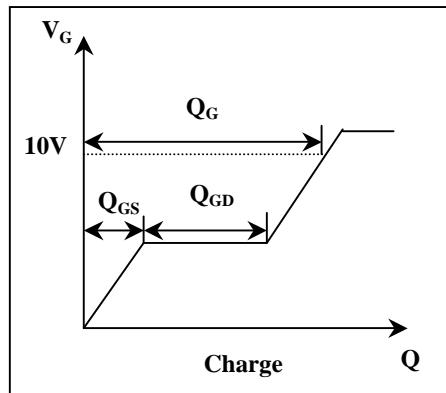
**Fig 9. Maximum Safe Operating Area**



**Fig 10. Effective Transient Thermal Impedance**



**Fig 11. Switching Time Waveform**



**Fig 12. Gate Charge Waveform**